

February 25 – 27, 2019

The Florida Hotel & Conference Center | Orlando, Florida

1500 Sand Lake Road, Orlando, Florida 32809

1-800-588-4656

## **TE- 22 | February 27 | 8:00 AM - 12:00 PM | 1/2-Day (4 hours)**

**Course Title:** Understanding Pass/Fail Measurement Decision Risk and how to comply with ISO/IEC 17025:2017

**Instructor:** Jonathan Harben, Keysight Technologies

**Course Description:** This tutorial will cover:

- What is measurement decision risk?
- Specific vs. global (average) risk
- When to use each type
- Techniques for estimating approximate per cent risk
- Inputs needed
- Tables and figures to interpolate
- Importance of considering both False accept and false reject risk
- Level of risk associated with several common decision rules in use today.
- Guidance flowchart for general selection of appropriate decision rules
- Class examples
- Class exercises.

**Instructor Biography:** Jonathan Harben is the Chief Metrologist for Keysight Technologies Services Solutions Group where he is responsible for global metrology decisions related to measurement traceability, measurement decision risk management, and harmonization of best practices. He started his career as a Metrologist at NASA's Kennedy Space Center (KSC) where he worked in the Standards Lab, maintaining electrical reference standards for multiple measurement disciplines. He joined Keysight Technologies in Santa Rosa, California in 2013. Jonathan earned a B.S. in Electrical Engineering from the University of Florida, and a Masters degree in Optics from the University of Central Florida College of Optics and Photonics (CREOL). Jon has been active in NCSLI since 2010 and is author or co-author of 10 papers, and has been an active contributor to 170 series committees